ABSTRACT OF THE DISCLOSURE

According to one embodiment, a programmable logic assembly (200) may include a
nonvolatile memory (202) may be coupled to an associated volatile programmable logic
device (PLD) (204). Built-in-self-test (BIST) data (208) may be stored in a nonvolatile
memory (202) that places the volatile PLD (204) in a self-test configuration. If a volatile
PLD (204) passes a self-test, user data (210) may be stored in a nonvolatile memory (202)
that places a volatile PLD (204) into a user determined configuration.